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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

Product Status	Obsolete
Core Processor	RL78
Core Size	16-Bit
Speed	32MHz
Connectivity	CSI, I ² C, LINbus, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	38
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 5.5V
Data Converters	A/D 12x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	52-LQFP
Supplier Device Package	52-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f104jcdfa-v0

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

[44-pin, 48-pin, 52-pin, 64-pin products (code flash memory 96 KB to 256 KB)]

Caution This outline describes the functions at the time when Peripheral I/O redirection register 0, 1 (PIOR0, 1) are set to 00H.

					(1/2)					
		44-pin	48-pin	52-pin	64-pin					
	Item	R5F104Fx	R5F104Gx	R5F104Jx	R5F104Lx					
		(x = F to H, J)	(x = F to H, J)	(x = F to H, J)	(x = F to H, J)					
Code flash mer	mory (KB)	96 to 256	96 to 256	96 to 256	96 to 256					
Data flash men	nory (KB)	8	8	8	8					
RAM (KB)		12 to 24 Note	12 to 24 Note	12 to 24 Note	12 to 24 Note					
Address space		1 MB								
Main system	High-speed system	X1 (crystal/ceramic) os	cillation, external main	system clock input (EX	CLK)					
clock	clock	HS (high-speed main) mode: 1 to 20 MHz (VDD = 2.7 to 5.5 V),								
		HS (high-speed main) mode: 1 to 16 MHz (VDD = 2.4 to 5.5 V),								
		LS (low-speed main) mode: 1 to 8 MHz (VDD = 1.8 to 5.5 V),								
		LV (low-voltage main) mode: 1 to 4 MHz (VDD = 1.6 to 5.5 V)								
	High-speed on-chip	HS (high-speed main) mode: 1 to 32 MHz (VDD = 2.7 to 5.5 V),								
	oscillator clock (fiH)	HS (high-speed main)	mode: 1 to 16 MHz (V	DD = 2.4 to 5.5 V),						
		LS (low-speed main) m	node: 1 to 8 MHz (Vc	D = 1.8 to 5.5 V),						
		LV (low-voltage main)	mode: 1 to 4 MHz (VD	D = 1.6 to 5.5 V)						
Subsystem clo	ck	XT1 (crystal) oscillation, external subsystem clock input (EXCLKS) 32.768 kHz								
Low-speed on-	chip oscillator clock	15 kHz (TYP.): Vod = 1	.6 to 5.5 V							
General-purpos	se register	8 bits \times 32 registers (8	bits \times 8 registers \times 4 ba	anks)						
Minimum instru	iction execution time	0.03125 μs (High-spee	d on-chip oscillator clo	ck: fiн = 32 MHz operat	ion)					
		0.05 μs (High-speed sy	ystem clock: fmx = 20 N	IHz operation)						
		30.5 µs (Subsystem cl	ock: fsuв = 32.768 kHz	operation)						
Instruction set		Data transfer (8/16 bi	its)							
		Adder and subtractor/logical operation (8/16 bits) Multiplication (8 bits × 8 bits 16 bits × 16 bits > 0 bits × 20 bi								
		• Multiplication (8 bits \times 8 bits, 16 bits \times 16 bits), Division (16 bits \div 16 bits, 32 bits \div 32 bits)								
		Multiplication and Accumulation (16 bits × 16 bits + 32 bits)								
I/O port	Total									
			34		48					
		5	5	5	48					
		5		1	1					
	N sh anan drain 1/0	_	1	1	1					
	(6 V tolerance)	4	4	4	4					
Timer	16-bit timer	8 channels								
		(TAU: 4 channels, Time	er RJ: 1 channel, Timer	RD: 2 channels, Timer	RG: 1 channel)					
	Watchdog timer	1 channel								
	Real-time clock (RTC)	1 channel								
	12-bit interval timer	1 channel								
	Timer output	Timer outputs: 14 channels								
		PWM outputs: 9 channels								
	RTC output	1								
		• 1 Hz (subsystem cloc	ck: fsuв = 32.768 kHz)							

(Note is listed on the next page.)

RENESAS

(R20UT2944).

 Note
 The flash library uses RAM in self-programming and rewriting of the data flash memory.

 The target products and start address of the RAM areas used by the flash library are shown below.

 R5F104xL (x = G, L, M, P): Start address F3F00H

 For the RAM areas used by the flash library, see Self RAM list of Flash Self-Programming Library for RL78 Family





TCY vs VDD (LS (low-speed main) mode)

TCY vs VDD (LV (low-voltage main) mode)





(2) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output, corresponding CSI00 only)

Parameter	Symbol	Conditions		HS (high-s main) mo	HS (high-speed main) mode		LS (low-speed main) mode		LV (low-voltage main) mode	
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy1	tkcy1 ≥ 2/fclk	$4.0~V \leq EV_{DD0} \leq 5.5~V$	62.5		250		500		ns
			$2.7~V \leq EV_{DD0} \leq 5.5~V$	83.3		250		500		ns
SCKp high-/low-level	tкнı,	$4.0 \; V \leq EV_{\text{DD0}}$	$4.0 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}$			tксү1/2 - 50		tксү1/2 - 50		ns
width	tĸ∟1	$2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}$		tксү1/2 - 10		tксү1/2 - 50		tксү1/2 - 50		ns
SIp setup time (to SCKp \uparrow)	tsiĸ1	$4.0 \; V \leq EV_{\text{DD0}}$	$1.0 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}$			110		110		ns
Note 1		$2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}$		33		110		110		ns
SIp hold time (from SCKp↑) ^{Note 2}	tksi1	$2.7~V \leq EV_{DD0} \leq 5.5~V$		10		10		10		ns
Delay time from SCKp↓ to SOp output ^{Note 3}	tkso1	C = 20 pF Note	4		10		10		10	ns

(TA = -40 to +85°C, 2.7 V \leq EVDD0 = EVDD1 \leq VDD \leq 5.5 V, VSS = EVSS0 = EVSS1 = 0 V)

Note 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The Slp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 4. C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remark 1. This value is valid only when CSI00's peripheral I/O redirect function is not used.

Remark 2. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0),

g: PIM and POM numbers (g = 1)

Remark 3. fMCK: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00))



Note 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Parameter	Symbol	Conditions		HS (high-s main) mo	peed ode	LS (low-speed mode	d main)	LV (low-vo main) mo	ltage ode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkCY1	tксү1 ≥ 4/fcLк	$2.7~V \leq E_{VDD0} \leq 5.5~V$	125		500		1000		ns
			$2.4~\text{V} \leq \text{EV}_{\text{DD0}} \leq 5.5~\text{V}$	250		500		1000		ns
			$1.8~V \leq EV_{DD0} \leq 5.5~V$	500		500		1000		ns
			$1.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}$	1000		1000		1000		ns
			$1.6 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}$	—		1000		1000		ns
SCKp high-/low-level	tĸнı,	$4.0 \text{ V} \leq \text{EV}_{\text{DDO}}$	0 ≤ 5.5 V	tксү1/2 - 12		tксү1/2 - 50		tксү1/2 - 50		ns
width	tKL1	$2.7 \text{ V} \leq \text{EV}_{\text{DDO}}$	$\leq 5.5 V$	tксү1/2 - 18		tксү1/2 - 50		tксү1/2 - 50		ns
		$2.4 \text{ V} \leq \text{EV}_{\text{DDO}}$	$0 \leq 5.5 \text{ V}$	tксү1/2 - 38		tксү1/2 - 50		tксү1/2 - 50		ns
		$1.8 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}$		tксү1/2 - 50		tксү1/2 - 50		tксү1/2 - 50		ns
		$1.7 \text{ V} \leq \text{EV}_{\text{DDO}}$	$\leq 5.5 V$	tксү1/2 - 100		tксү1/2 - 100		tксү1/2 - 100		ns
		$1.6 \text{ V} \leq \text{EV}_{\text{DDO}}$	$\leq 5.5 V$	—		tксү1/2 - 100		tксү1/2 - 100		ns
SIp setup time	tsik1	$4.0 \text{ V} \leq \text{EV}_{\text{DDO}}$	$\leq 5.5 V$	44		110		110		ns
(to SCKp↑) ^{Note 1}		$2.7 \text{ V} \leq \text{EV}_{\text{DDO}}$	$\leq 5.5 V$	44		110		110		ns
		$2.4 \text{ V} \leq \text{EV}_{\text{DDO}}$	$V \leq EV$ DD0 $\leq 5.5 V$			110		110		ns
		$1.8 \text{ V} \leq \text{EV}_{\text{DDO}}$	$\leq 5.5 V$	110		110		110		ns
		$1.7 \text{ V} \leq \text{EV}_{\text{DDO}}$	$\leq 5.5 V$	220		220		220		ns
		$1.6 \text{ V} \leq \text{EV}_{\text{DDO}}$	$\leq 5.5 V$	—		220		220		ns
SIp hold time	tksi1	$1.7 \text{ V} \leq \text{EV}_{\text{DDC}}$	$\leq 5.5 V$	19		19		19		ns
(from SCKp↑) Note 2		$1.6 \text{ V} \leq \text{EV}_{\text{DDO}}$	$\leq 5.5 V$	—		19		19		ns
Delay time from SCKp↓ to SOp output	tkso1	$1.7 V \le EV_{DDC}$ C = 30 pF Note	o ≤ 5.5 V e 4		25		25		25	ns
		$1.6 V \le EV_{DDC}$ C = 30 pF Note	o ≤ 5.5 V e 4		_		25		25	ns

(3) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output) (TA = -40 to +85°C, 1.6 V \leq EVDD0 = EVDD1 \leq VDD \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V)

Note 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The Slp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 4. C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remark 1. p: CSI number (p = 00, 01, 10, 11, 20, 21, 30, 31), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM number (g = 0, 1, 3 to 5, 14)

Remark 2. fMCK: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))



Remark 1. p: CSI number (p = 00, 01, 10, 11, 20, 21, 30, 31), m: Unit number (m = 0, 1),

n: Channel number (n = 0 to 3), g: PIM number (g = 0, 1, 3 to 5, 14)

Remark 2. fMCK: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,

n: Channel number (mn = 00 to 03, 10 to 13))



UART mode connection diagram (during communication at different potential)



UART mode bit width (during communication at different potential) (reference)





Remark 1. $Rb[\Omega]$: Communication line (TxDq) pull-up resistance,

Cb[F]: Communication line (TxDq) load capacitance, Vb[V]: Communication line voltage

Remark 2. q: UART number (q = 0 to 3), g: PIM and POM number (g = 0, 1, 5, 14)

Remark 3. fMCK: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))

Remark 4. UART2 cannot communicate at different potential when bit 1 (PIOR01) of peripheral I/O redirection register 0 (PIOR0) is 1.



RL78/G14

(9) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (slave mode, SCKp... external clock input)

Parameter	Symbol	Cor	HS (hig main)	h-speed mode	LS (low main)	r-speed mode	LV (low- main)	-voltage mode	Unit	
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tксү2	$4.0~V \leq EV_{DD0} \leq 5.5~V,$	24 MHz < fмск	14/fмск		—		_		ns
Note 1		$2.7~V \leq V_b \leq 4.0~V$	$20 \text{ MHz} < f_{MCK} \leq 24 \text{ MHz}$	12/fмск		—				ns
			$8 \text{ MHz} < \text{fmck} \le 20 \text{ MHz}$	10/fмск		_				ns
			$4 \text{ MHz} < f_{MCK} \le 8 \text{ MHz}$	8/fмск		16/fмск		_		ns
			fмск ≤ 4 MHz	6/fмск		10/fмск		10/fмск		ns
		$2.7~V \leq EV_{DD0} < 4.0~V,$	24 MHz < fмск	20/fмск		—		_		ns
		$2.3 \text{ V} \leq \text{V}_b \leq 2.7 \text{ V}$	20 MHz < fмск ≤ 24 MHz	16/fмск		—		_		ns
			16 MHz < fмск ≤ 20 MHz	14/fмск		—		_		ns
			$8 \text{ MHz} < \text{fmck} \le 16 \text{ MHz}$	12/fмск		_		_		ns
			$4 \text{ MHz} < \text{fmck} \le 8 \text{ MHz}$	8/fмск		16/fмск		_		ns
			fмск ≤ 4 MHz	6/fмск		10/fмск		10/fмск		ns
		$1.8 \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V},$	24 MHz < fмск	48/fмск		_		_		ns
		1.6 V ≤ Vb ≤ 2.0 V Note 2	20 MHz < fмск ≤ 24 MHz	36/fмск		_		_		ns
			16 MHz < fmck \leq 20 MHz	32/fмск		—		_		ns
			$8 \text{ MHz} < \text{fmck} \le 16 \text{ MHz}$	26/fмск		_		_		ns
			$4 \text{ MHz} < \text{fmck} \le 8 \text{ MHz}$	16/fмск		16/fмск		_		ns
			fмск ≤ 4 MHz	10/fмск		10/fмск		10/fмск		ns
SCKp high-/ low-level width	tкн2, tкL2	$4.0 \text{ V} \le \text{EV}_{\text{DD0}} \le 5.5 \text{ V}, 2$	$2.7 \text{ V} \leq V_b \leq 4.0 \text{ V}$	tксү2/2 - 12		tксү2/2 - 50		tксү2/2 - 50		ns
		$2.7 \text{ V} \le \text{EV}_{\text{DD0}} < 4.0 \text{ V}, 2$	$2.3 \text{ V} \leq V_b \leq 2.7 \text{ V}$	tксү2/2 - 18		tксү2/2 - 50		tксү2/2 - 50		ns
		$1.8 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V}, T$	$1.6 \text{ V} \leq V_b \leq 2.0 \text{ V} \text{ Note } 2$	tксү2/2 - 50		tксү2/2 - 50		tксү2/2 - 50		ns
SIp setup time (to SCKp↑) ^{Note 3}	tsık2	$4.0 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}, 2$	$2.7 \text{ V} \leq V_b \leq 4.0 \text{ V}$	1/fмск + 20		1/fмск + 30		1/fмск + 30		ns
		$2.7 \text{ V} \le \text{EV}_{\text{DD0}} < 4.0 \text{ V}, 2$	$2.3 \text{ V} \leq \text{V}_b \leq 2.7 \text{ V}$	1/fмск + 20		1/fмск + 30		1/fмск + 30		ns
		$1.8 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V}, ^{2}$	$1.6 \text{ V} \leq V_b \leq 2.0 \text{ V} \text{ Note 2}$	1/fмск + 30		1/fмск + 30		1/fмск + 30		ns
SIp hold time (from SCKp↑) Note 4	tksi2			1/fмск + 31		1/fмск + 31		1/fмск + 31		ns
Delay time from SCKp↓ to SOp	tkso2	4.0 V \leq EVDD0 \leq 5.5 V, 2 Cb = 30 pF, Rb = 1.4 kΩ	$2.7 \text{ V} \leq \text{Vb} \leq 4.0 \text{ V},$		2/fмск + 120		2/fмск + 573		2/fмск + 573	ns
output ^{Note 5}		$\begin{array}{l} 2.7 \ V \leq EV_{DD0} < 4.0 \ V, 2 \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	$2.3 \text{ V} \le \text{V}_{\text{b}} \le 2.7 \text{ V},$		2/fмск + 214		2/fмск + 573		2/fмск + 573	ns
		$\begin{array}{l} 1.8 \ V \leq EV_{DD0} < 3.3 \ V, \\ C_b = 30 \ pF, \ R_V = 5.5 \ k\Omega \end{array}$	$1.6 \text{ V} \le \text{V}_b \le 2.0 \text{ V} \text{ Note 2},$		2/fмск + 573		2/fмск + 573		2/fмск + 573	ns

($(T_A = -40 \text{ to } +85^{\circ}\text{C})$	18V<	< Vnn < 5 5 V	Vss = EVsso	= FVSS1 = 0	٧١
	1A = -40 10 + 00 0	1.0 V -		, v 33 – L v 330		• /

(Notes, Caution, and Remarks are listed on the next page.)



Parameter	Symbol	Conditions	HS (high-speed r mode	nain)	LS (low-speed m mode	nain)	LV (low-voltage r mode	nain)	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Data setup time (reception)	tsu:dat	$\begin{array}{l} 4.0 \ V \leq EV_{DD0} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	1/fмск + 135 Note 3		1/fмск + 190 Note 3		1/fмск + 190 Note 3		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD0} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	1/fмск + 135 Note 3		1/fмск + 190 Note 3		1/fмск + 190 Note 3		ns
			1/fмск + 190 Note 3		1/f _{MCK} + 190 Note 3		1/f _{MCK} + 190 Note 3		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD0} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 100 \ p\text{F}, \ R_b = 2.7 \ k\Omega \end{array}$	1/fмск + 190 Note 3		1/fmck + 190 Note 3		1/fмск + 190 Note 3		ns
			1/fмск + 190 Note 3		1/fмск + 190 Note 3		1/fмск + 190 Note 3		ns
Data hold time (transmission)	thd:dat		0	305	0	305	0	305	ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD0} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	0	305	0	305	0	305	ns
		$\begin{array}{l} 4.0 \ V \leq EV_{DD0} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 100 \ p\text{F}, \ R_b = 2.8 \ k\Omega \end{array}$	0	355	0	355	0	355	ns
		$\label{eq:2.7} \begin{array}{l} 2.7 \ V \leq EV_{DD0} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	0	355	0	355	0	355	ns
			0	405	0	405	0	405	ns

(10) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified I²C mode)

(TA = -40 to +85°C, 1.8 V \leq EVDD0 = EVDD1 \leq VDD \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V)

(2/2)

Note 1. The value must also be equal to or less than fmck/4.

Note 2. Use it with $EV_{DD0} \ge V_b$.

Note 3. Set the fMCK value to keep the hold time of SCLr = "L" and SCLr = "H".

Caution Select the TTL input buffer and the N-ch open drain output (VDD tolerance (for the 30- to 52-pin products)/EVDD tolerance (for the 64- to 100-pin products)) mode for the SDAr pin and the N-ch open drain output (VDD tolerance (for the 30- to 52-pin products)/EVDD tolerance (for the 64- to 100-pin products)) mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

(**Remarks** are listed on the next page.)



Simplified I²C mode connection diagram (during communication at different potential)



Simplified I²C mode serial transfer timing (during communication at different potential)



- **Remark 1.** Rb[Ω]: Communication line (SDAr, SCLr) pull-up resistance, Cb[F]: Communication line (SDAr, SCLr) load capacitance, Vb[V]: Communication line voltage
- Remark 2. r: IIC number (r = 00, 01, 10, 11, 20, 30, 31), g: PIM, POM number (g = 0, 1, 3 to 5, 14)
- Remark 3. fMCK: Serial array unit operation clock frequency
 - (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1), n: Channel number (n = 0, 2), mn = 00, 01, 02, 10, 12, 13)



(3) When reference voltage (+) = VDD (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = Vss (ADREFM = 0), target pin: ANI0 to ANI14, ANI16 to ANI20, internal reference voltage, and temperature sensor output voltage

(TA = -40 to +85°C, 1.6 V \leq EVDD0 = EVDD1 \leq VDD \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V, Reference voltage (+) = VDD, Reference voltage (-) = Vss)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error Note 1	AINL	10-bit resolution	$1.8 \text{ V} \leq \text{V}\text{DD} \leq 5.5 \text{ V}$		1.2	±7.0	LSB
			$1.6 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}^{\text{Note 3}}$		1.2	±10.5	LSB
Conversion time	tconv	10-bit resolution	$3.6~V \le V_{DD} \le 5.5~V$	2.125		39	μs
		Target pin: ANI0 to ANI14, ANI16 to ANI20	$2.7~V \leq V_{DD} \leq 5.5~V$	3.1875		39	μs
			$1.8~V \le V_{DD} \le 5.5~V$	17		39	μs
			$1.6~V \leq V_{DD} \leq 5.5~V$	57		95	μs
		10-bit resolution	$3.6~V \le V_{DD} \le 5.5~V$	2.375		39	μs
		Target pin: internal reference voltage, and temperature sensor output voltage	$2.7~V \leq V_{DD} \leq 5.5~V$	3.5625		39	μs
		(HS (high-speed main) mode)	$2.4~V \leq V \text{DD} \leq 5.5~V$	17		39	μs
Zero-scale error Notes 1, 2	Ezs	10-bit resolution	$1.8~V \le V_{DD} \le 5.5~V$			±0.60	%FSR
			1.6 V \leq VDD \leq 5.5 V Note 3			±0.85	%FSR
Full-scale error Notes 1, 2	Efs	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
			$1.6~V \leq V_{DD} \leq 5.5~V$ Note 3			±0.85	%FSR
Integral linearity error Note 1	ILE	10-bit resolution	$1.8~V \le V_{DD} \le 5.5~V$			±4.0	LSB
			$1.6~V \leq V_{DD} \leq 5.5~V$ Note 3			±6.5	LSB
Differential linearity error	DLE	10-bit resolution	$1.8~V \le V_{DD} \le 5.5~V$			±2.0	LSB
Note 1			$1.6~V \leq V_{DD} \leq 5.5~V$ Note 3			±2.5	LSB
Analog input voltage	Vain	ANI0 to ANI14		0		Vdd	V
		ANI16 to ANI20		0		EV _{DD0}	V
		Internal reference voltage (2.4 V \leq VDD \leq 5.5 V, HS (high-speed main) n	\ \	/ _{BGR} Note	4	V	
		Temperature sensor output voltage (2.4 V \leq VDD \leq 5.5 V, HS (high-speed main) n	Temperature sensor output voltage (2.4 V \leq VDD \leq 5.5 V, HS (high-speed main) mode)				

Note 1. Excludes quantization error (±1/2 LSB).

Note 2. This value is indicated as a ratio (% FSR) to the full-scale value.

Note 3. When the conversion time is set to 57 μ s (min.) and 95 μ s (max.).

Note 4. Refer to 2.6.2 Temperature sensor characteristics/internal reference voltage characteristic.



(4) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: ANI0, ANI2 to ANI14, ANI16 to ANI20

(TA = -40 to +85°C, 2.4 V \leq VDD \leq 5.5 V, 1.6 V \leq EVDD = EVDD1 \leq VDD, Vss = EVss0 = EVss1 = 0 V, Reference voltage (+) = VBGR ^{Note 3}, Reference voltage (-) = AVREFM = 0 V ^{Note 4}, HS (high-speed main) mode)

Parameter	Symbol	Со	MIN.	TYP.	MAX.	Unit	
Resolution	RES				8		bit
Conversion time	tCONV	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
Zero-scale error Notes 1, 2	Ezs	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±0.60	% FSR
Integral linearity error Note 1	ILE	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±2.0	LSB
Differential linearity error Note 1	DLE	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±1.0	LSB
Analog input voltage	Vain			0		VBGR Note 3	V

Note 1. Excludes quantization error (±1/2 LSB).

Note 2. This value is indicated as a ratio (% FSR) to the full-scale value.

Note 3. Refer to 2.6.2 Temperature sensor characteristics/internal reference voltage characteristic.

Note 4. When reference voltage (-) = Vss, the MAX. values are as follows.

Zero-scale error:Add $\pm 0.35\%$ FSR to the MAX. value when reference voltage (-) = AVREFM.Integral linearity error:Add ± 0.5 LSB to the MAX. value when reference voltage (-) = AVREFM.Differential linearity error:Add ± 0.2 LSB to the MAX. value when reference voltage (-) = AVREFM.



Absolute Maximum Ratings

(2/2)

Parameter	Symbols		Conditions	Ratings	Unit
Output current, high	Іон1	Per pin	P00 to P06, P10 to P17, P30, P31, P40 to P47, P50 to P57, P64 to P67, P70 to P77, P80 to P87, P100 to P102, P110, P111, P120, P130, P140 to P147	-40	mA
		Total of all pins	P00 to P04, P40 to P47, P102, P120, P130, P140 to P145	-70	mA
		-170 mA	P05, P06, P10 to P17, P30, P31, P50 to P57, P64 to P67, P70 to P77, P80 to P87, P100, P101, P110, P111, P146, P147	-100	mA
	Іон2	Per pin	P20 to P27, P150 to P156	-0.5	mA
		Total of all pins		-2	mA
Output current, low	IOL1	Per pin	P00 to P06, P10 to P17, P30, P31, P40 to P47, P50 to P57, P64 to P67, P70 to P77, P80 to P87, P100 to P102, P110, P111, P120, P130, P140 to P147	40	mA
		Total of all pins	P00 to P04, P40 to P47, P102, P120, P130, P140 to P145	70	mA
		170 mA	P05, P06, P10 to P17, P30, P31, P50 to P57, P60 to P67, P70 to P77, P80 to P87, P100, P101, P110, P111, P146, P147	100	mA
	IOL2	Per pin	P20 to P27, P150 to P156	1	mA
		Total of all pins		5	mA
Operating ambient	Та	In normal o	pperation mode	-40 to +105	°C
temperature		In flash me	mory programming mode		
Storage temperature	Tstg			-65 to +150	°C

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



(5) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode)

(TA = -40 to +105°C, 2.4 V \leq EVDD0 = EVDD1 \leq VDD \leq 5.5 V, VSS = EVSS0 = EVSS1 = 0 V)

(1/2)

Parameter	Symbol			Conditions	HS (high-s	peed main) mode	Unit
					MIN.	MAX.	
Transfer rate		reception	4.0 2.7	$\begin{split} V &\leq E V_{DD0} \leq 5.5 \text{ V}, \\ V &\leq V_b \leq 4.0 \text{ V} \end{split}$		f _{MCK} /12 Note 1	bps
				Theoretical value of the maximum transfer rate f_{MCK} = f_{CLK} Note 3		2.6	Mbps
			2.7 2.3	$\begin{split} &V \leq EV_{DD0} < 4.0 \text{ V}, \\ &V \leq V_b \leq 2.7 \text{ V} \end{split}$		f _{MCK} /12 Note 1	bps
				Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK} Note 3$		2.6	Mbps
			2.4 1.6	$\begin{split} &V \leq EV_{DD0} < 3.3 \text{ V}, \\ &V \leq V_{b} \leq 2.0 \text{ V} \end{split}$		f _{MCK} /12 Notes 1, 2	bps
				Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK} Note 3$		2.6	Mbps

Note 1. Transfer rate in the SNOOZE mode is 4800 bps only.

However, the SNOOZE mode cannot be used when FRQSEL4 = 1.

```
Note 2. The following conditions are required for low voltage interface when EVDD0 < VDD.
```

 $2.4 \text{ V} \leq \text{EV}_{\text{DD0}} < 2.7 \text{ V}$: MAX. 1.3 Mbps

- **Note 3.** The maximum operating frequencies of the CPU/peripheral hardware clock (fcLK) are: HS (high-speed main) mode: $32 \text{ MHz} (2.7 \text{ V} \le \text{VDD} \le 5.5 \text{ V})$
 - 16 MHz (2.4 V \leq VDD \leq 5.5 V)
- Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance (for the 30- to 52-pin products)/EVDD tolerance (for the 64- to 100-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
- Remark 1. Vb [V]: Communication line voltage
- **Remark 2.** q: UART number (q = 0 to 3), g: PIM and POM number (g = 0, 1, 5, 14)
- Remark 3. fMCK: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13)

Remark 4. UART2 cannot communicate at different potential when bit 1 (PIOR01) of peripheral I/O redirection register 0 (PIOR0) is 1.



(6) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output)

(TA = -40 to +105°C, 2.4 V \leq EVDD0 =	= EVDD1 \leq V	$DD \leq \textbf{5.5 V, Vss} = \textbf{EVsso}$	= EVSS1 = 0 V)		(3/3)
Parameter	Symbol	Conditions	HS (high-spe	ed main) mode	Unit
			MIN.	MAX.	
SIp setup time (to SCKp↓) ^{Note}	tsiк1		88		ns
		$\begin{array}{l} 2.7 \; V \leq EV_{DD0} < 4.0 \; V, \\ 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	88		ns
		$\begin{array}{l} 2.4 \; V \leq EV_{DD0} < 3.3 \; V, \\ 1.6 \; V \leq V_b \leq 2.0 \; V, \\ C_b = 30 \; pF, \; R_b = 5.5 \; k\Omega \end{array}$	220		ns
SIp hold time (from SCKp↓) ^{Note}	tksi1		38		ns
		$\begin{array}{l} 2.7 \; V \leq EV_{DD0} < 4.0 \; V, \\ 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	38		ns
		$\label{eq:2.4} \begin{array}{l} 2.4 \ V \leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	38		ns
Delay time from SCKp↑ to SOp output ^{Note}	tkso1			50	ns
		$\begin{array}{l} 2.7 \; V \leq EV_{DD0} < 4.0 \; V, \\ 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$		50	ns
		$\begin{array}{l} 2.4 \; V \leq EV_{DD0} < 3.3 \; V, \\ 1.6 \; V \leq V_b \leq 2.0 \; V, \\ C_b = 30 \; pF, \; R_b = 5.5 \; k\Omega \end{array}$		50	ns

Note When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

(Remarks are listed on the next page.)



Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (for the 30- to 52-pin products)/EVDD tolerance (for the 64- to 100-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

Simplified I²C mode connection diagram (during communication at different potential)



Simplified I²C mode serial transfer timing (during communication at different potential)



- **Remark 1.** Rb[Ω]: Communication line (SDAr, SCLr) pull-up resistance, Cb[F]: Communication line (SDAr, SCLr) load capacitance, Vb[V]: Communication line voltage
- Remark 2. r: IIC number (r = 00, 01, 10, 11, 20, 30, 31), g: PIM, POM number (g = 0, 1, 3 to 5, 14)
- Remark 3. fMCK: Serial array unit operation clock frequency
 - (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1), n: Channel number (n = 0, 2), mn = 00, 01, 02, 10, 12, 13)



(2) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: ANI16 to ANI20

Parameter	Symbol	Conditions			TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error Note 1	AINL	10-bit resolution EVDD0 ≤ AVREFP = VDD Notes 3, 4	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le 5.5 \text{ V}$		1.2	±5.0	LSB
Conversion time	tconv	10-bit resolution Target ANI pin: ANI16 to ANI20	$3.6~V \leq V_{DD} \leq 5.5~V$	2.125		39	μs
			$2.7~V \leq V_{DD} \leq 5.5~V$	3.1875		39	μs
			$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
Zero-scale error Notes 1, 2	Ezs	10-bit resolution EVDD0 ≤ AVREFP = VDD Notes 3, 4	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le 5.5 \text{ V}$			±0.35	%FSR
Full-scale error Notes 1, 2	Efs	10-bit resolution EVDD0 ≤ AVREFP = VDD Notes 3, 4	$2.4 \text{ V} \leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			±0.35	%FSR
Integral linearity error Note 1	ILE	10-bit resolution EVDD0 ≤ AVREFP = VDD Notes 3, 4	$2.4 \text{ V} \leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			±3.5	LSB
Differential linearity error Note 1	DLE	10-bit resolution EVDD0 ≤ AVREFP = VDD Notes 3, 4	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le 5.5 \text{ V}$			±2.0	LSB
Analog input voltage	VAIN	ANI16 to ANI20		0		AVREFP and EVDD0	V

(TA = -40 to +105°C, 2.4 V \leq EVDD0 = EVDD1 \leq VDD \leq 5.5 V, 2.4 V \leq AVREFP \leq VDD \leq 5.5 V, Vss = EVsso = EVss1 = 0 V, Reference voltage (+) = AVREFP, Reference voltage (-) = AVREFM = 0 V)

Note 1. Excludes quantization error (±1/2 LSB).

Note 2. This value is indicated as a ratio (%FSR) to the full-scale value.

Note 3. When $EVDD0 \le AVREFP \le VDD$, the MAX. values are as follows.

	Overall error:	Add ±1.0 LSB to the MAX. value when AVREFP = VDD.				
	Zero-scale error/Full-scale error:	Add $\pm 0.05\%$ FSR to the MAX. value when AVREFP = VDD.				
	Integral linearity error/ Differential linearity error:	Add ±0.5 LSB to the MAX. value when AVREFP = VDD.				
Note 4.	4. When $AV_{REFP} < EV_{DD0} \le V_{DD}$, the MAX. values are as follows.					
	Overall error:	Add ±4.0 LSB to the MAX. value when AVREFP = VDD.				
	<u> </u>					

Zero-scale error/Full-scale error:

Add ±0.20%FSR to the MAX. value when AVREFP = VDD. Integral linearity error/ Differential linearity error: Add ±2.0 LSB to the MAX. value when AVREFP = VDD.



3.6.6 LVD circuit characteristics

(1) Reset Mode and Interrupt Mode

(TA = -40 to +105°C, VPDR \leq VDD \leq 5.5 V, VSS = 0 V)

Parameter		Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Voltage detection	Supply voltage level	VLVD0	Rising edge	3.90	4.06	4.22	V
threshold			Falling edge	3.83	3.98	4.13	V
		VLVD1	Rising edge	3.60	3.75	3.90	V
			Falling edge	3.53	3.67	3.81	V
		VLVD2	Rising edge	3.01	3.13	3.25	V
			Falling edge	2.94	3.06	3.18	V
		VLVD3	Rising edge	2.90	3.02	3.14	V
			Falling edge	2.85	2.96	3.07	V
		VLVD4	Rising edge	2.81	2.92	3.03	V
			Falling edge	2.75	2.86	2.97	V
		VLVD5	Rising edge	2.70	2.81	2.92	V
			Falling edge	2.64	2.75	2.86	V
		VLVD6	Rising edge	2.61	2.71	2.81	V
			Falling edge	2.55	2.65	2.75	V
		VLVD7	Rising edge	2.51	2.61	2.71	V
			Falling edge	2.45	2.55	2.65	V
Minimum pulse wid	lth	tLW		300			μs
Detection delay tim	le					300	μs



R5F104LCALA, R5F104LDALA, R5F104LEALA, R5F104LFALA, R5F104LGALA, R5F104LHALA, R5F104LJALA R5F104LKALA, R5F104LLALA

R5F104LCGLA,R5F104LDGLA, R5F104LEGLA, R5F104LFGLA, R5F104LGGLA, R5F104LHGLA, R5F104LJGLA R5F104LKGLA, R5F104LLGLA



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RENESAS

4.9 80-pin products

R5F104MFAFB, R5F104MGAFB, R5F104MHAFB, R5F104MJAFB R5F104MFDFB, R5F104MGDFB, R5F104MHDFB, R5F104MJDFB R5F104MFGFB, R5F104MGGFB, R5F104MHGFB, R5F104MJGFB

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LFQFP80-12x12-0.50	PLQP0080KE-A	P80GK-50-8EU-2	0.53



NOTE

Each lead centerline is located within 0.08 mm of its true position at maximum material condition.

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